

## 20V N+N-Channel Enhancement Mode MOSFET

### Description

The AP50H02DF3 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 20V$   $I_D = 50A$

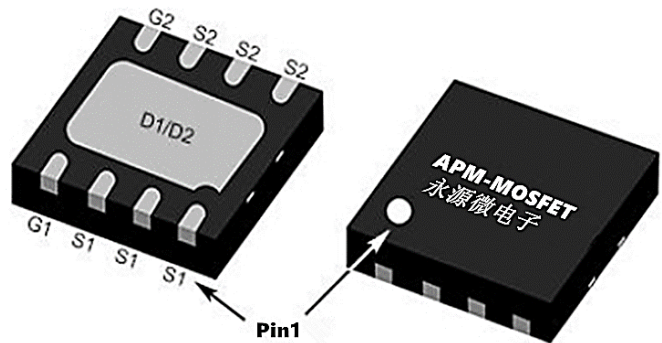
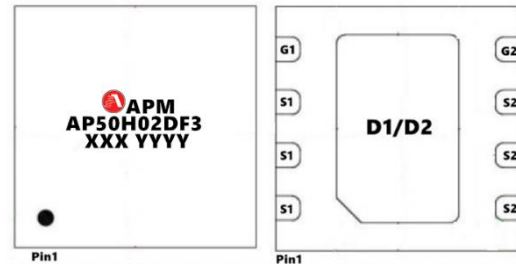
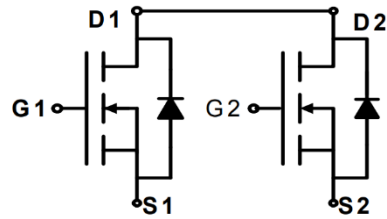
$R_{DS(ON)} < 8.5m\Omega$  @  $V_{GS}=4.5V$  (Type: 6.2m $\Omega$ )

### Application

3.3V MCU Drive

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP50H02DF3	DFN3*3-8L	AP50H02DF XXX YYYY	5000

### Absolute Maximum Ratings ( $T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	20	V
VGSS	Gate-Source Voltage	$\pm 12$	V
$I_{D@TA=25^{\circ}C}$	Continuous Drain Current, $V_{GS}$ @ 4.5V	50	A
$I_{D@TA=70^{\circ}C}$	Continuous Drain Current, $V_{GS}$ @ 4.5V	30	A
IDM	Pulsed Drain Current <sup>note1</sup>	120	A
EAS	Single Pulsed Avalanche Energy <sup>note2</sup>	147.6	mJ
PD@TA=25 $^{\circ}C$	Power Dissipation	37	W
TJ, TSTG	Operating and Storage Temperature Range	-55 to +175	$^{\circ}C$
R $\theta$ JA	Thermal Resistance Junction-Ambient <sup>1</sup>	85	$^{\circ}C/W$
R $\theta$ JC	Thermal Resistance, Junction to Case	2	$^{\circ}C/W$

**20V N+N-Channel Enhancement Mode MOSFET**
**Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	20	24	-	V
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =20V, V <sub>GS</sub> =0V,	-	-	1.0	μA
IGSS	Gate to Body Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±12V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	0.4	0.7	1.1	V
RDS(on)	Static Drain-Source on-Resistance note3	V <sub>GS</sub> =4.5V, I <sub>D</sub> =25A	-	6.2	8.5	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =10A	-	8.8	13	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1.0MHz	-	1458	-	pF
C <sub>oss</sub>	Output Capacitance		-	238	-	pF
Crss	Reverse Transfer Capacitance		-	212	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =10V, I <sub>D</sub> =25A, V <sub>GS</sub> =4.5V	-	19	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	3	-	nC
Q <sub>gd</sub>	Gate-Drain(“Miller”) Charge		-	6.4	-	nC
td(on)	Turn-on Delay Time	V <sub>DS</sub> =10V, I <sub>D</sub> =10A, R <sub>GEN</sub> =3Ω, V <sub>GS</sub> =4.5V	-	10	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	21	-	ns
td(off)	Turn-off Delay Time		-	39	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	19	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	50	A
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	200	A
VSD	Drain to Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =30A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time	IF=20A,dI/dt=100A/μs	-	25	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	20	-	nC

**Note :**

- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、The test condition is  $T_J=25^{\circ}\text{C}$ ,  $V_{DD}=10V$ ,  $V_G=4.5V$ ,  $L=0.5mH$ ,  $R_G=25\Omega$ ,  $I_{AS}=12A$
- 4、The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



### Typical Characteristics

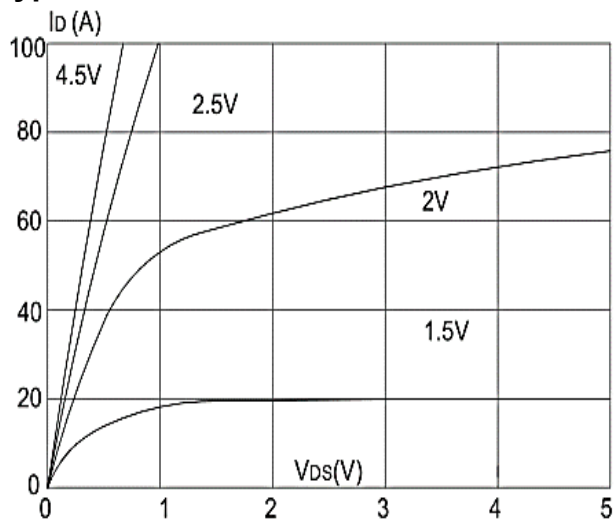


Figure1: Output Characteristics

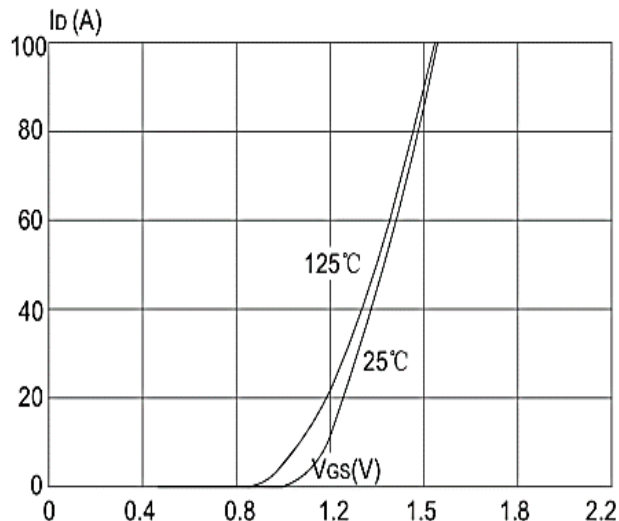


Figure 2: Typical Transfer Characteristics

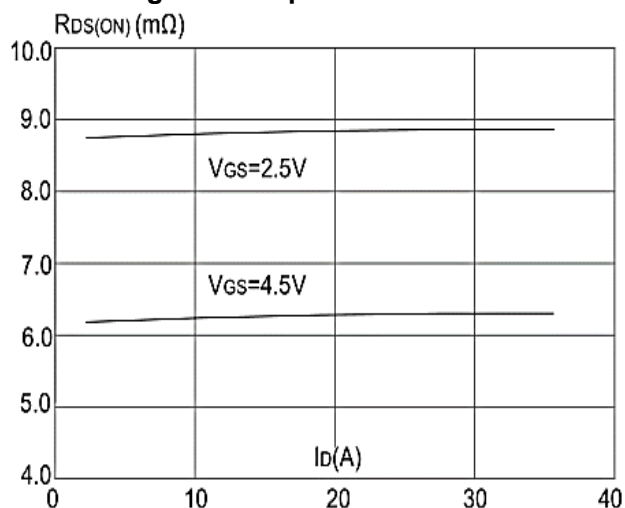


Figure 3: On-resistance vs. Drain Current

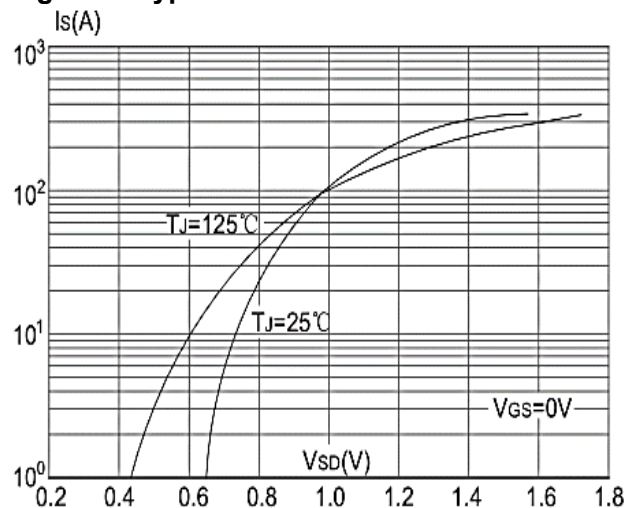


Figure 4: Body Diode Characteristics

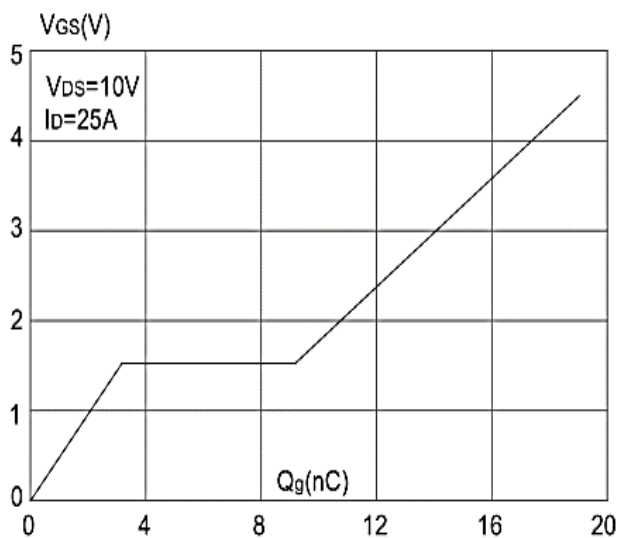


Figure 5: Gate Charge Characteristics

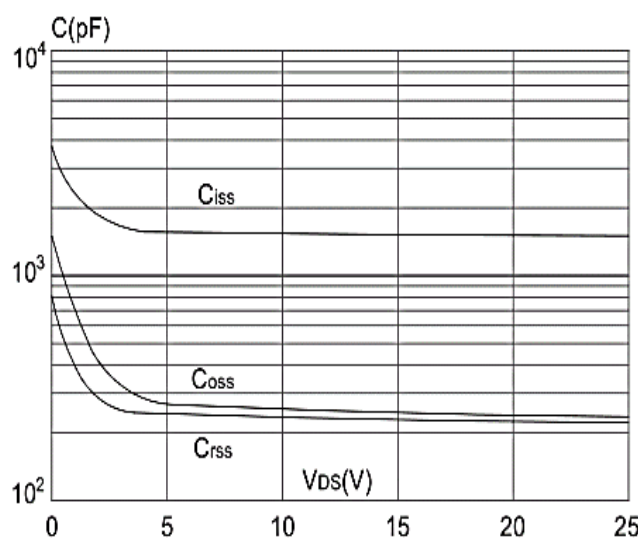
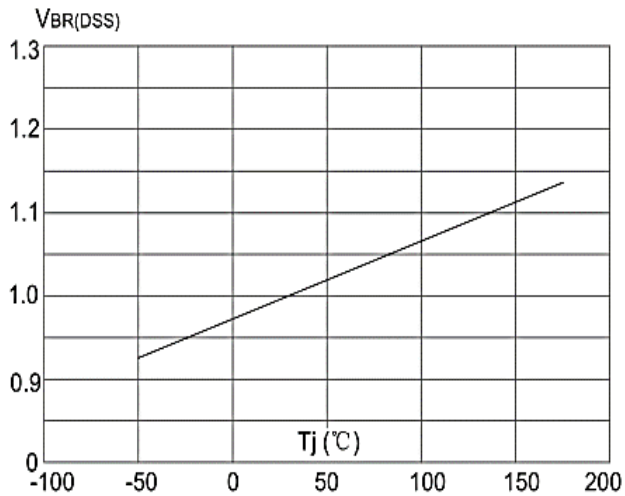
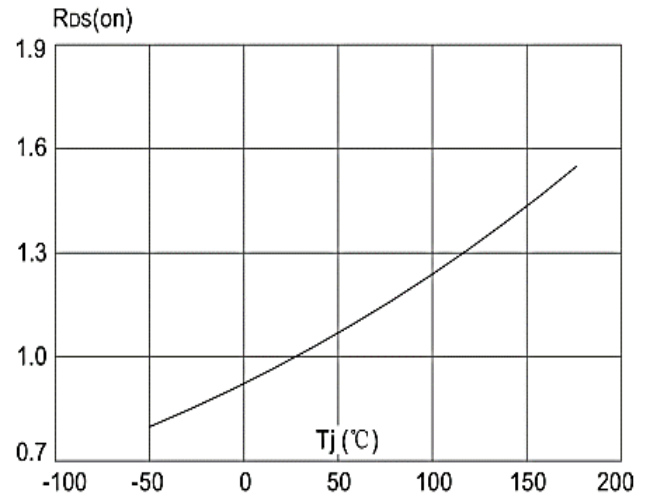


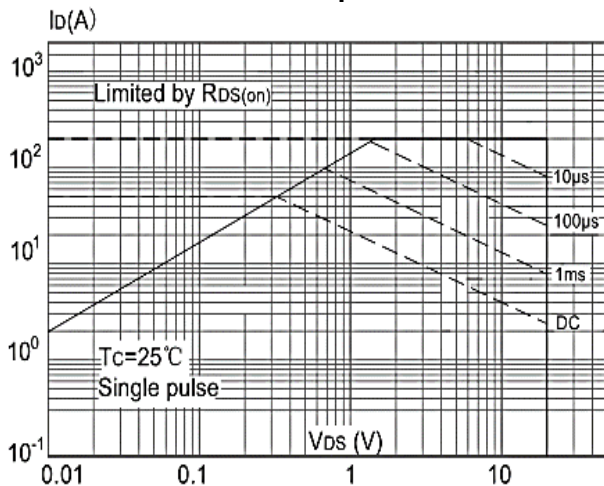
Figure 6: Capacitance Characteristics



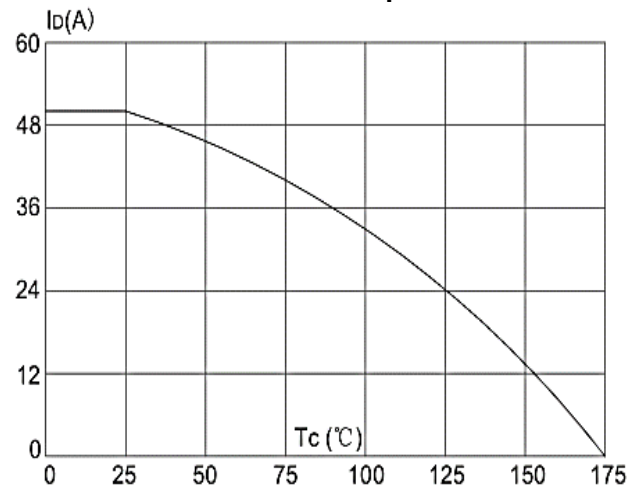
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



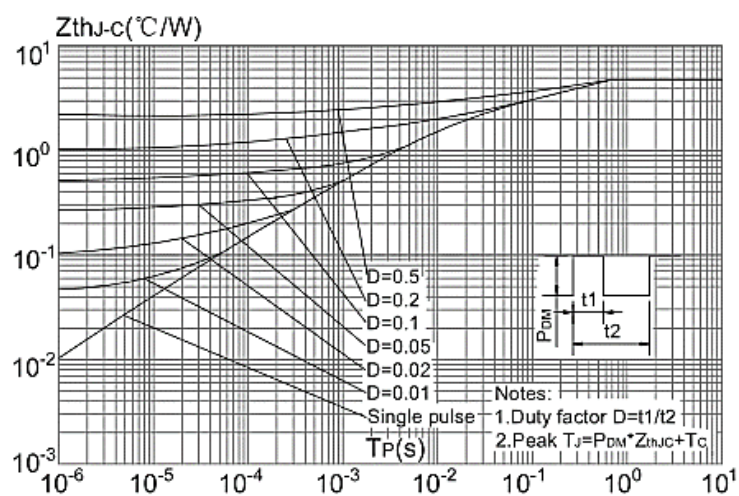
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area vs. Case Temperature**



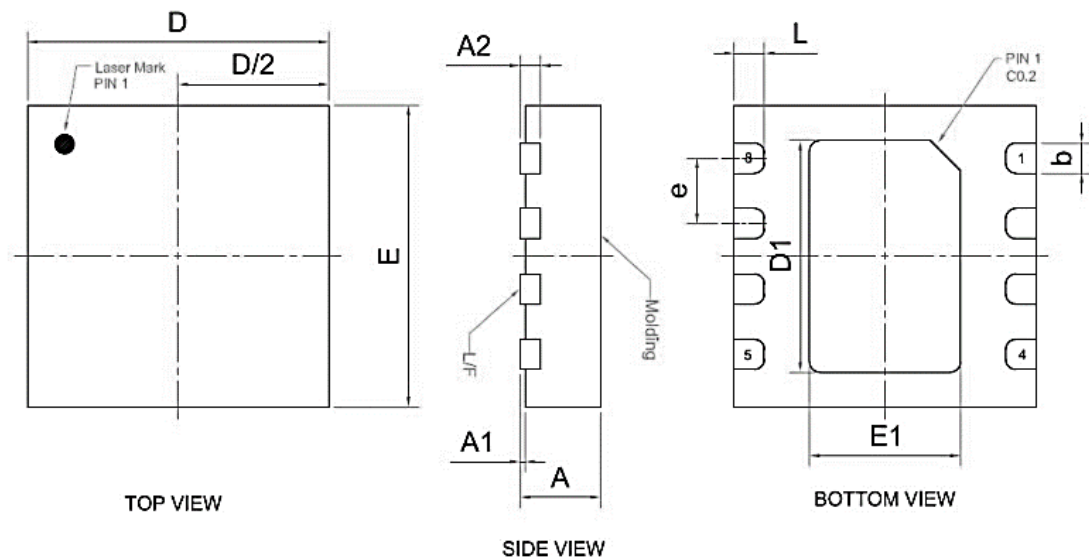
**Figure 10: Maximum Continuous Drain Current vs. Case Temperature**



**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case**



**Package Mechanical Data-DFN3X3-8L**



Symbol	Dim in mm	
	Min	Max
A	0.70	0.80
A1	0.00	0.05
A2	0.203REF	
b	0.25	0.35
D	2.90	3.10
E	2.90	3.10
D1	2.20	2.40
E1	1.40	1.60
L	0.20	0.40
e	0.65BSC	

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Edition	Date	Change
REV1.0	2024/3/31	Initial release

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